

Notice of References Cited

Application/Control No.

10/559,497

Applicant(s)/Patent Under
Reexamination
FUJII, TAKEHIRO

Examiner

MORGAN VARNER

Art Unit

2895

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2004/0056260	03-2004	Slater et al.	257/079
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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